OLYMPUS®

A Brief History of Some of Our Most Important

Industrial Product Milestones

We began making microscopes for the life sciences in 1919. 10 years later, we began applying our microscope technology to industrial applications. The rest is history!

1929 We make our first foray into industrial inspection with the MC metallurgical microscope

1955 Our first metrology microscope debuts—the MI micro interferometer

1968 Leveraging technological development from our medical business, we launch the IFS series, our first industrial RVI products

1973 Launch of the Model 5221, the world's first commercial ultrasonic thickness gage with multi-mode measurement and swing-set velocity calibration

1984 The debut of the EPOCH® 2002, the world's first field portable, all digital flaw detector

1988 We launch the world's first thickness gage with internal data logger—the 22DL

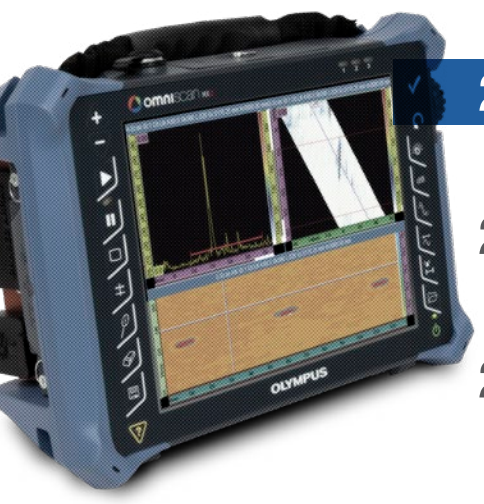
1994 We bring datalogging and file management capabilities to portable UT with the EPOCH III flaw detector

2001 The XT, our first portable XRF analyzer, launches

2003 Phased array goes portable with the launch of the OmniScan® flaw detector

2008 XRD analyzers are finally small enough to fit on a benchtop or take into the field with the launch of the BTX® and TERRA® analyzers

2010 Portable, functional, and tough—the EPOCH 600 flaw detector debuts



2011 Our best-selling portable phased array device—the OmniScan MX2—launches

2012 Microscopes go digital with the launch of the DSX series

2014 The NORTEC® 600 eddy current flaw detector debuts

2016 Launch of the first portable XRF analyzer designed to meet IP64/65—the Vanta™ analyzer

2017 Our most portable ultrasonic flaw detector yet—the EPOCH 6LT—launches

HD RVI™ arrives with the launch of the IPLEX NX videoscope

A new era of working connected begins with the launch of the Olympus Scientific Cloud™